

EEE 598: RF Test

Course Description: This course will cover current production test schemes for mixed-signal and RF circuits, the economics of production test and recent research techniques in reducing the production test cost.

Course topics

- Data analysis and probability
- Measurement accuracy
- Specification definitions
- Test optimization
- Sampling theory
- DC and parametric tests
- DAC and ADC testing
- Analog Channel testing
- Introduction to RF test
- RF test methods
- DIB design and simulation
- Outlier analysis
- Defect-oriented test